TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

# 2SK2991

# DC-DC Converter Relay Drive and Motor Drive Applications

• Low drain-source ON resistance : RDS (ON) =  $1.35 \Omega$  (typ.) • High forward transfer admittance :  $|Y_{fs}| = 4.0 S$  (typ.) • Low leakage current : IDSS =  $100 \mu A$  (max) (VDS = 500 V) • Enhancement mode :  $V_{th} = 2.0 \sim 4.0 V$  (VDS = 10 V, ID = 1 mA)

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	500	V	
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		$V_{DGR}$	500	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	ID	5	Α	
	Pulse (Note 1)	I <sub>DP</sub>	20	Α	
Drain power dissipation (Tc = 25°C)		PD	50	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	180	mJ	
Avalanche current		I <sub>AR</sub>	5	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.5	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	83.3	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

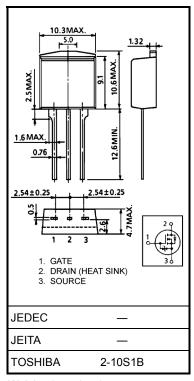
Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 12.2 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 5 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

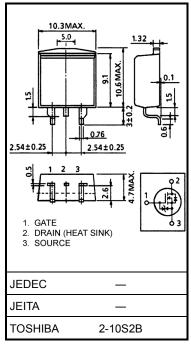
This transistor is an electrostatic-sensitive device.

Please handle with caution.

Unit: mm



Weight: 1.5 g (typ.)



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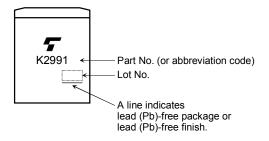
## **Electrical Characteristics (Ta = 25°C)**

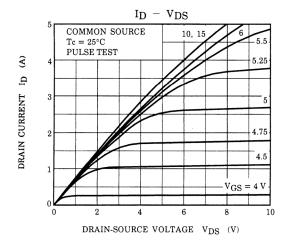
Charae	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Gate-source br	eakdown voltage	V (BR) GSS	I <sub>G</sub> = ±10 μA, V <sub>DS</sub> = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ
Drain-source bi	reakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	500	_		٧
Gate threshold	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	٧
Drain-source O	N resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.5 A	_	1.35	1.50	Ω
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.5 A	2.5	4.0	_	S
Input capacitano	ce	C <sub>iss</sub>		_	780	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	60	_	pF
Output capacitance		Coss		_	200	_	
Switching time Fall ti	Rise time	t <sub>r</sub>	$V_{GS} = 0V$ $I_{D} = 2.5A$ $V_{OUT}$ $R_{L} = 90\Omega$	_	12	_	
	Turn-on time	t <sub>on</sub>		_	25	_	ne
	Fall time	t <sub>f</sub>		_	15	_	ns ns
	Turn-off time	t <sub>off</sub>	$\begin{array}{c} V_{DD} \stackrel{.}{=} 225V \\ Duty \leq 1\%, \ t_W = 10 \mu s \end{array}$	_	60	_	
Total gate charge (gate-source plus gate-drain)		Qg	V <sub>DD</sub> ≈ 400 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A	_	17		nC
Gate-source charge		Q <sub>gs</sub>		_	11	_	
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	6	_	

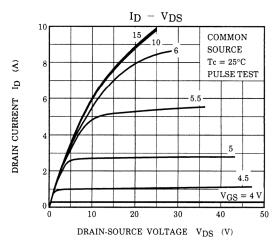
### Source-Drain Ratings and Characteristics (Ta = 25°C)

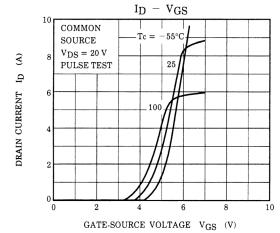
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	20	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V, dI <sub>DR</sub> / dt = 100 A / μs	_	1400	_	ns
Reverse recovery charge	Q <sub>rr</sub>		_	9	_	μC

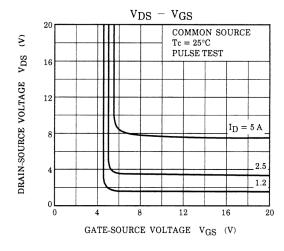
## Marking

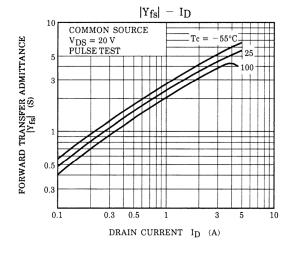


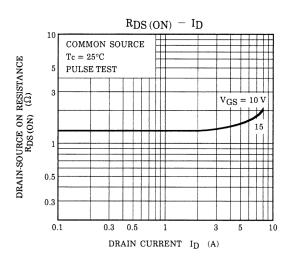


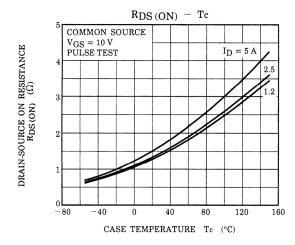


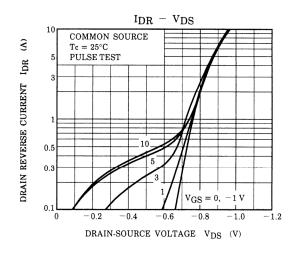


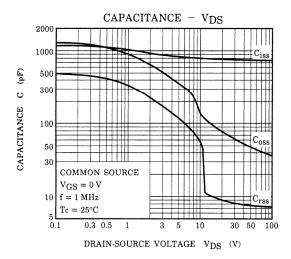


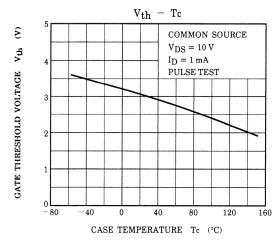


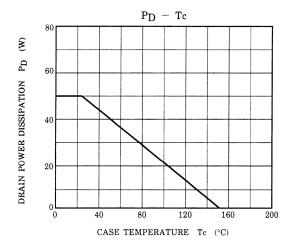


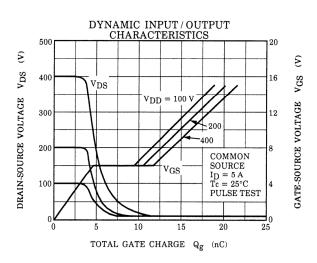




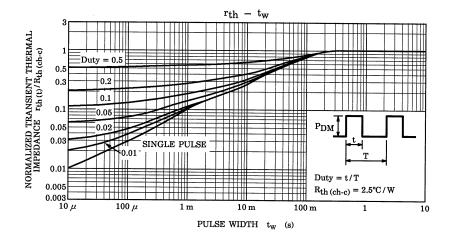


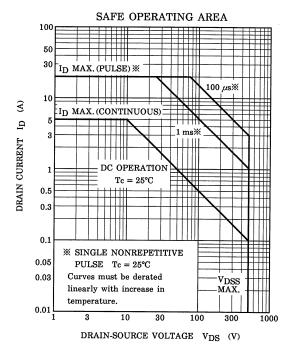


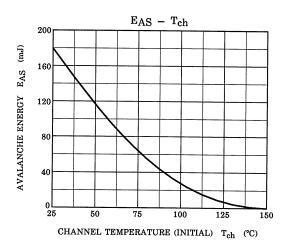


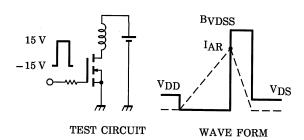


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$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 12.2~mH \end{aligned} \quad E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right)$$

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